

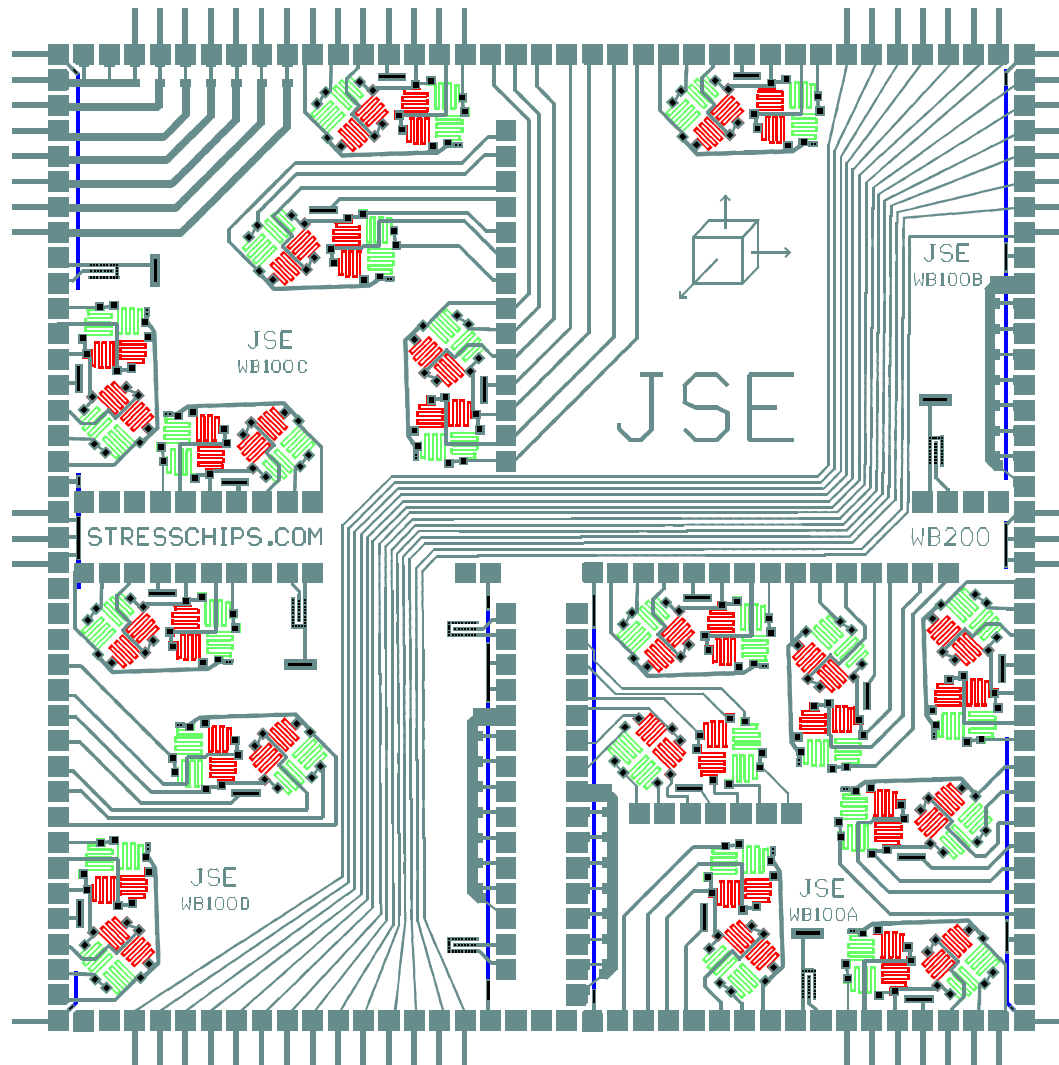
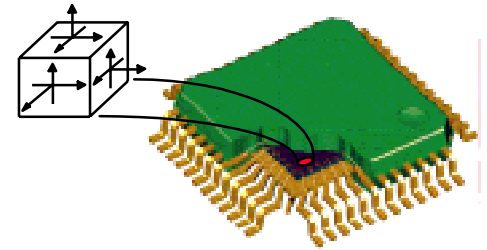
STRESS TEST CHIPS

WIRE BOND DIE

JS Engineering, L.L.C.
P. O. Box 2084
Auburn, AL 36831-2084
USA

www.stresschips.com

WIRE BOND TEST DIE



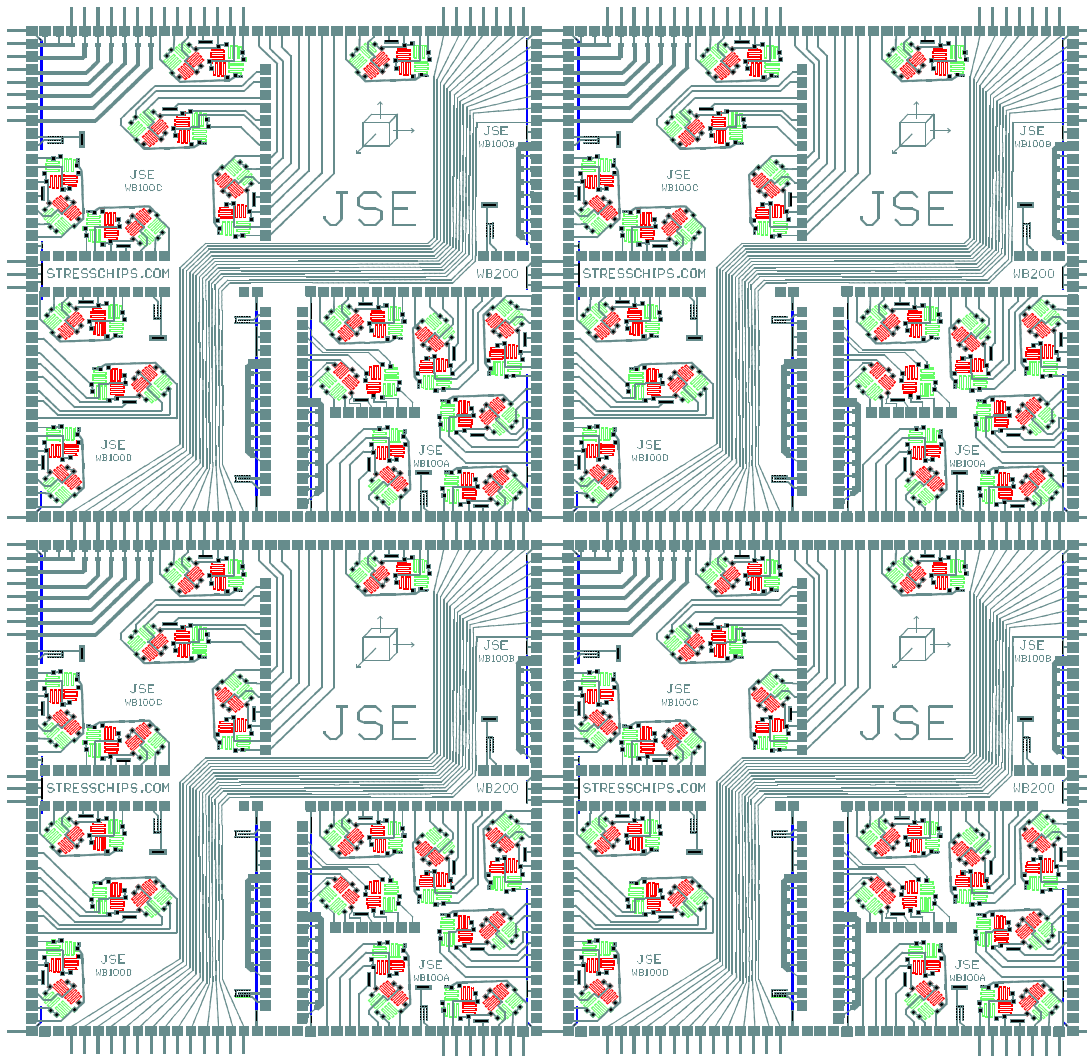
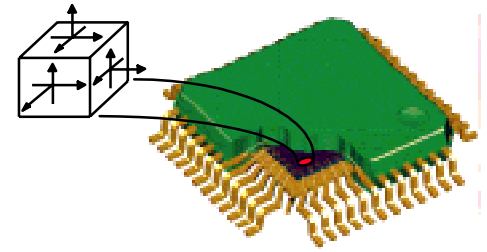
WB200

- 5 x 5 mm Die
- Chip ID (Fuses)
- 10 Rosettes
- Sub Surface Heater
- Diode Temperature Sensors

WB100A

- 2.5 mm x 2.5 mm Die
- Chip ID
- 7 Rosettes
- Sub Surface Heater
- Diode Temperature Sensors

WIRE BOND TEST DIE

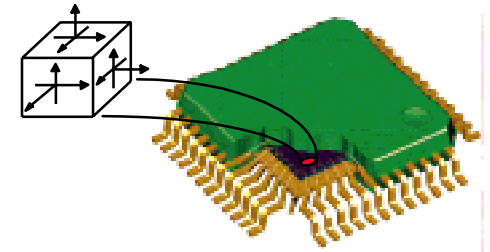


WB400

- 2 x 2 Array of the WB200
- 10 x 10 mm Die
- Chip ID
- 23 Rosettes
- Sub Surface Heater
- Diode Temperature Sensors

THERMAL TEST

Wire Bond Test Chip



Chip Heater Test

Voltage = 3 V, Current = 0.062 A, Resistance = 50.6 Ω

